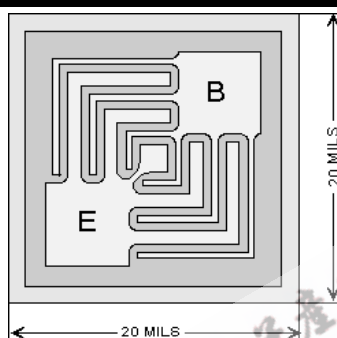


**Chip Type 2C2907A**  
**Geometry 0600**  
**Polarity PNP**

**Generic Packaged Parts:**  
**2N2905, 2N2905A, 2N2907,**  
**2N2907A**



[Request Quotation](#)

Chip type **2C2907A** by Semicoa Semiconductors provides performance similar to these devices.

**Part Numbers:**

[2N2905](#), [2N2905A](#), [2N2905AL](#), [2N2907](#), [2N2907A](#),  
[2N2907AUB](#), [SD2907A](#), [SD2907AF](#), [SQ2907A](#),  
[SQ2907AF](#), [2N3486](#), [2N3486A](#), [2N6987](#), [2N6989](#)

**Product Summary:**

**APPLICATIONS:** Designed for general purpose switching and amplifier applications.

**Features:** [Radiation graphs available](#)

### Mechanical Specifications

Metallization	Top	Al - 18 kÅ min.
	Backside	Au - 6.5 kÅ nom.
Bonding Pad Size	Emitter	4.0 mils x 4.0 mils
	Base	4.0 mils x 4.0 mils
Die Thickness	8 mils nominal	
Chip Area	20 mils x 20 mils	
Top Surface	Silox Passivated	

### Electrical Characteristics

$T_A = 25^\circ\text{C}$

Parameter	Test conditions	Min	Max	Unit
$BV_{CEO}$	$I_C = 10\text{ mA}$ , $I_B = 0$	60	---	V dc
$BV_{CBO}$	$I_C = 10\text{ }\mu\text{A}$ , $I_E = 0$	60	---	V dc
$BV_{EBO}$	$I_E = 10\text{ }\mu\text{A}$ , $I_C = 0$	5.0	---	V dc
$I_{CBO}$	$V_{CB} = 50\text{ V}$ , $I_E = 0$	---	10	nA
$h_{FE}$	$I_C = 150\text{ mA dc}$ , $V_{CE} = 10\text{ V}$	100	300	---

Due to limitations of probe testing, only dc parameters are tested. This must be done with pulse width less than 300  $\mu\text{s}$ , duty cycle less than 2%.